## **Power MOSFET**

# 9.0 A, 52 V, N-Channel, Logic Level, Clamped MOSFET w/ESD Protection in a DPAK Package

## **Benefits**

- High Energy Capability for Inductive Loads
- Low Switching Noise Generation

## **Features**

- Diode Clamp Between Gate and Source
- ESD Protection HBM 5000 V
- Active Over-Voltage Gate to Drain Clamp
- Scalable to Lower or Higher R<sub>DS(on)</sub>
- Internal Series Gate Resistance
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

## **Applications**

Automotive and Industrial Markets:
 Solenoid Drivers, Lamp Drivers, Small Motor Drivers

## MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise noted)

Rating	Symbol	Value	Unit
Drain-to-Source Voltage Internally Clamped	V <sub>DSS</sub>	52–59	V
Gate-to-Source Voltage - Continuous	V <sub>GS</sub>	±15	V
Drain Current – Continuous @ $T_A = 25^{\circ}C$ – Single Pulse ( $t_p = 10 \mu s$ )	I <sub>D</sub> I <sub>DM</sub>	9.0 35	Α
Total Power Dissipation @ T <sub>A</sub> = 25°C	P <sub>D</sub>	1.74	W
Operating and Storage Temperature Range	T <sub>J</sub> , T <sub>stg</sub>	-55 to 175	°C
Single Pulse Drain-to-Source Avalanche Energy – Starting $T_J$ = 125°C ( $V_{DD}$ = 50 V, $I_{D(pk)}$ = 1.5 A, $V_{GS}$ = 10 V, $I_{C}$ = 25 $I_{C}$	E <sub>AS</sub>	160	mJ
Thermal Resistance, Junction-to-Case Junction-to-Ambient (Note 1) Junction-to-Ambient (Note 2)	$\begin{array}{c} R_{\thetaJC} \\ R_{\thetaJA} \\ R_{\thetaJA} \end{array}$	5.2 72 100	°C/W
Maximum Lead Temperature for Soldering Purposes, 1/8" from Case for 10 seconds	TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

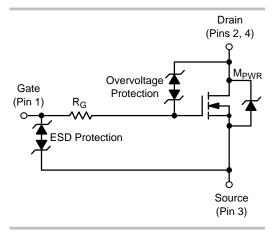
- 1. When surface mounted to a FR4 board using 1" pad size, (Cu area 1.127 in<sup>2</sup>).
- When surface mounted to a FR4 board using minimum recommended pad size, (Cu area 0.412 in<sup>2</sup>).



## ON Semiconductor®

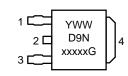
## www.onsemi.com

V <sub>DSS</sub> (Clamped)	R <sub>DS(ON)</sub> TYP	I <sub>D</sub> MAX (Limited)
52 V	90 mΩ	9.0 A



## DPAK CASE 369C STYLE 2

## MARKING DIAGRAM



Υ	= Year	1 = Gate
WW	= Work Week	2 = Drain
XXXXX	= 05ACL or 05BCL	3 = Source
G	= Pb-Free Package	4 = Drain

#### ORDERING INFORMATION

Device	Package	Shipping <sup>†</sup>
NID9N05ACLT4G	DPAK (Pb-Free)	2500/Tape & Reel
NID9N05BCLT4G	DPAK (Pb-Free)	2500/Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

## $\textbf{ELECTRICAL CHARACTERISTICS} \ (T_J = 25^{\circ}\text{C unless otherwise noted})$

Characteristic		Symbol	Min	Тур	Max	Unit
OFF CHARACTERISTICS						
Drain–to–Source Breakdown Voltage (Note 3) ( $V_{GS} = 0 \text{ V}, I_D = 1.0 \text{ mA}, T_J = 25^{\circ}\text{C}$ ) ( $V_{GS} = 0 \text{ V}, I_D = 1.0 \text{ mA}, T_J = -40^{\circ}\text{C}$ to 125°C) Temperature Coefficient (Negative)		V <sub>(BR)DSS</sub>	52 50.8 -	55 54 –10	59 59.5 –	V V mV/°C
Zero Gate Voltage Drain Current $(V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V})$ $(V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 12 \text{ C})$	25°C)	I <sub>DSS</sub>	- -	_ _	10 25	μΑ
Gate-Body Leakage Current $(V_{GS} = \pm 8 \text{ V}, V_{DS} = 0 \text{ V})$ $(V_{GS} = \pm 14 \text{ V}, V_{DS} = 0 \text{ V})$		I <sub>GSS</sub>	- -	- ±22	±10 –	μΑ
ON CHARACTERISTICS (Note 3)		-				•
Gate Threshold Voltage (Note 3) (V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 100 μA) Threshold Temperature Coefficient (Negative)		V <sub>GS(th)</sub>	1.3	1.75 -4.5	2.5 -	V mV/°C
Static Drain-to-Source On-Resistance (Note 3)		R <sub>DS(on)</sub>	- - - 70 67	153 175 - 90 95	181 364 1210 - -	mΩ
Forward Transconductance (Note	3) $(V_{DS} = 15 \text{ V}, I_D = 9.0 \text{ A})$	9FS	-	24	ı	Mhos
DYNAMIC CHARACTERISTICS						
Input Capacitance		C <sub>iss</sub>	-	155	250	pF
Output Capacitance	$(V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}, f = 10 \text{ kHz})$	C <sub>oss</sub>	-	60	100	
Transfer Capacitance		C <sub>rss</sub>	-	25	40	
Input Capacitance		C <sub>iss</sub>	-	175	ı	pF
Output Capacitance	$(V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V}, f = 10 \text{ kHz})$	C <sub>oss</sub>	-	70	ı	
Transfer Capacitance		C <sub>rss</sub>	-	30	-	
SWITCHING CHARACTERISTICS	6 (Note 4)					
Turn-On Delay Time		t <sub>d(on)</sub>	-	130	200	ns
Rise Time	$(V_{GS} = 10 \text{ V}, V_{DD} = 40 \text{ V},$	t <sub>r</sub>	-	500	750	
Turn-Off Delay Time	$I_D = 9.0 \text{ A}, R_G = 9.0 \Omega$	t <sub>d(off)</sub>	-	1300	2000	
Fall Time		t <sub>f</sub>	-	1150	1850	
Turn-On Delay Time		t <sub>d(on)</sub>	-	200	ı	ns
Rise Time	$(V_{GS} = 10 \text{ V}, V_{DD} = 15 \text{ V},$	t <sub>r</sub>	-	500	-	
Turn-Off Delay Time	$I_D = 1.5 \text{ A}, R_G = 2 \text{ k}\Omega$	t <sub>d(off)</sub>	-	2500	-	
Fall Time		t <sub>f</sub>	-	1800	ı	
Turn-On Delay Time		t <sub>d(on)</sub>	-	120	-	ns
Rise Time	$(V_{GS} = 10 \text{ V}, V_{DD} = 15 \text{ V},$	t <sub>r</sub>	-	275	-	
Turn-Off Delay Time	$I_D = 1.5 \text{ A}, R_G = 50 \Omega)$	t <sub>d(off)</sub>	-	1600		
Fall Time		t <sub>f</sub>	-	1100	-	
Gate Charge		Q <sub>T</sub>	-	4.5	7.0	nC
	$(V_{GS} = 4.5 \text{ V}, V_{DS} = 40 \text{ V}, I_{D} = 9.0 \text{ A}) \text{ (Note 3)}$	Q <sub>1</sub>	-	1.2	-	
	1D = 3.0 A) (Note 3)		-	2.7	_	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.
 Switching characteristics are independent of operating junction temperatures.

## **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise noted)

Characteristic			Min	Тур	Max	Unit
SWITCHING CHARACTERIST	FICS (Note 4)				•	
Gate Charge		$Q_{T}$	-	3.6	_	nC
	(V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 15 V, I <sub>D</sub> = 1.5 A) (Note 3)	Q <sub>1</sub>	_	1.0	_	
	10 = 1.070 (1000 0)		_	2.0	-	
SOURCE-DRAIN DIODE CHA	ARACTERISTICS					•
Forward On-Voltage	$(I_S = 4.5 \text{ A}, V_{GS} = 0 \text{ V}) \text{ (Note 3)}$ $(I_S = 4.0 \text{ A}, V_{GS} = 0 \text{ V})$ $(I_S = 4.5 \text{ A}, V_{GS} = 0 \text{ V}, T_J = 125^{\circ}\text{C})$	V <sub>SD</sub>	- - -	0.86 0.845 0.725	1.2 - -	V
Reverse Recovery Time		t <sub>rr</sub>	-	700	_	ns
	$(I_S = 4.5 \text{ A}, V_{GS} = 0 \text{ V},$ $dI_S/dt = 100 \text{ A/}\mu\text{s}) \text{ (Note 3)}$	ta	_	200	_	
		t <sub>b</sub>	-	500	_	1
Reverse Recovery Stored Charge		$Q_{RR}$	_	6.5	_	μС
ESD CHARACTERISTICS						
Electro-Static Discharge	Human Body Model (HBM)	ESD	5000	_	_	V
Capability	Machine Model (MM)		500	_	_	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

<sup>3.</sup> Pulse Test: Pulse Width  $\leq$  300  $\mu$ s, Duty Cycle  $\leq$  2%.

<sup>4.</sup> Switching characteristics are independent of operating junction temperatures.

## **TYPICAL PERFORMANCE CURVES**

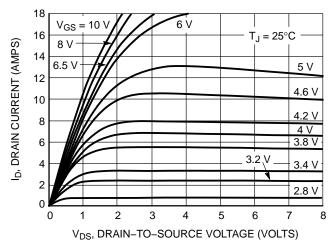


Figure 1. On-Region Characteristics

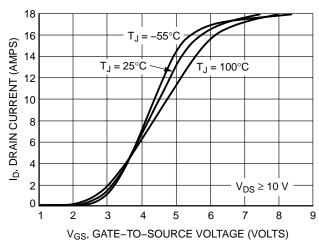


Figure 2. Transfer Characteristics

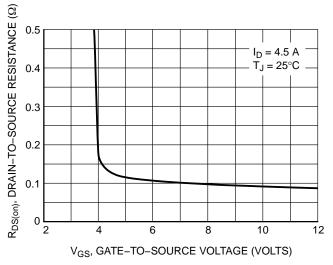


Figure 3. On–Resistance versus Gate–to–Source Voltage

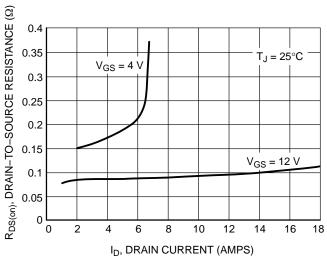


Figure 4. On-Resistance versus Drain Current and Gate Voltage

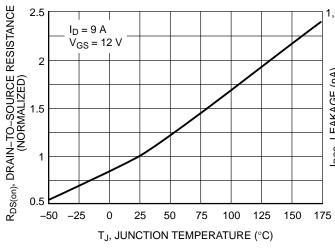


Figure 5. On–Resistance Variation with Temperature

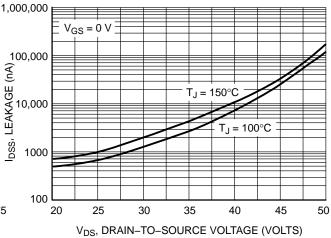


Figure 6. Drain-to-Source Leakage Current versus Voltage

## **TYPICAL PERFORMANCE CURVES**

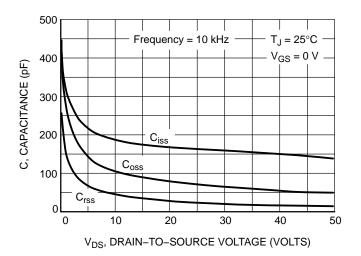


Figure 7. Capacitance Variation

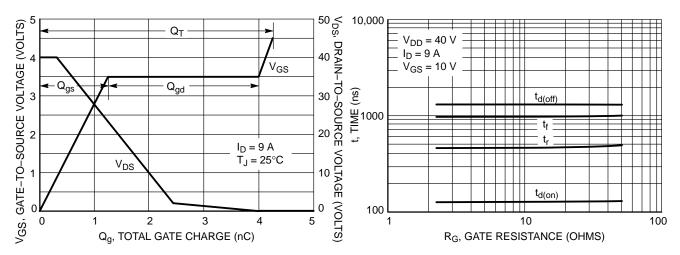


Figure 8. Gate-To-Source and Drain-To-Source Voltage versus Total Charge

Figure 9. Resistive Switching Time Variation versus Gate Resistance

## DRAIN-TO-SOURCE DIODE CHARACTERISTICS

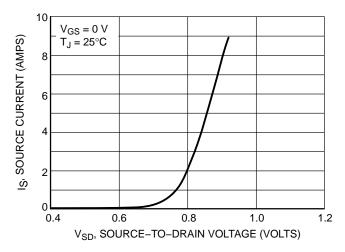


Figure 10. Diode Forward Voltage versus Current

## SAFE OPERATING AREA

The Forward Biased Safe Operating Area curves define the maximum simultaneous drain—to—source voltage and drain current that a transistor can handle safely when it is forward biased. Curves are based upon maximum peak junction temperature and a case temperature ( $T_{\rm C}$ ) of 25°C. Peak repetitive pulsed power limits are determined by using the thermal response data in conjunction with the procedures discussed in AN569, "Transient Thermal Resistance — General Data and Its Use."

Switching between the off–state and the on–state may traverse any load line provided neither rated peak current ( $I_{DM}$ ) nor rated voltage ( $V_{DSS}$ ) is exceeded and the transition time ( $t_pt_f$ ) do not exceed 10  $\mu s$ . In addition the total power averaged over a complete switching cycle must not exceed ( $T_{J(MAX)} - T_C$ )/( $R_{\theta JC}$ ).

A Power MOSFET designated E-FET can be safely used in switching circuits with unclamped inductive loads. For reliable operation, the stored energy from circuit inductance dissipated in the transistor while in avalanche must be less than the rated limit and adjusted for operating conditions differing from those specified. Although industry practice is to rate in terms of energy, avalanche energy capability is not a constant. The energy rating decreases non–linearly with an increase of peak current in avalanche and peak junction temperature.

Although many E–FETs can withstand the stress of drain–to–source avalanche at currents up to rated pulsed current ( $I_{DM}$ ), the energy rating is specified at rated continuous current ( $I_{D}$ ), in accordance with industry custom. The energy rating must be derated for temperature as shown in the accompanying graph (Figure 12). Maximum energy at currents below rated continuous  $I_{D}$  can safely be assumed to equal the values indicated.

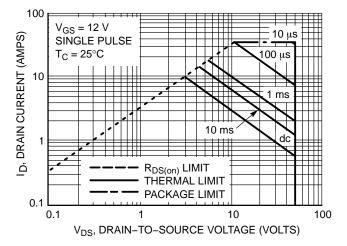


Figure 11. Maximum Rated Forward Biased Safe Operating Area

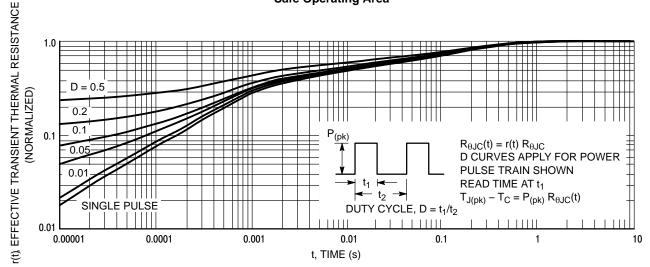
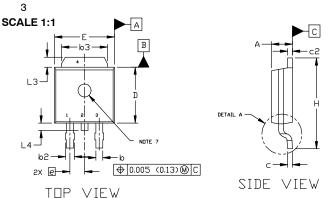


Figure 12. Thermal Response

## **DPAK (SINGLE GAUGE)**

CASE 369C ISSUE G

**DATE 31 MAY 2023** 

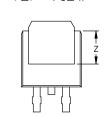


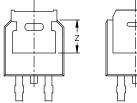


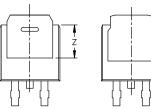
- DIMENSIONING AND TOLERANCING ASME Y14.5M, 1994. CONTROLLING DIMENSION: INCHES
- THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS 63,
- L3. AND Z. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH,
  PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR
  GATE BURRS SHALL NOT EXCEED 0.006 INCHES PER SIDE.
- DIMENSIONS D AND E ARE DETERMINED AT THE DUTERMOST EXTREMES OF THE PLASTIC BODY.

  DATUMS A AND B ARE DETERMINED AT DATUM PLANE H.
- OPTIONAL MOLD FEATURE.

DIM	INCHES		MILLIMETERS		
וווע	MIN.	MAX.	MIN.	MAX.	
Α	0.086	0.094	2.18	2.38	
A1	0.000	0.005	0.00	0.13	
b	0.025	0.035	0.63	0.89	
b2	0.028	0.045	0.72	1.14	
b3	0.180	0.215	4.57	5.46	
С	0.018	0.024	0.46	0.61	
c2	0.018	0.024	0.46	0.61	
D	0.235	0.245	5.97	6.22	
E	0.250	0.265	6.35	6.73	
е	0.090 BSC		2.29	BSC	
Н	0.370	0.410	9.40	10.41	
L	0.055	0.070	1.40	1.78	
L1	0.114 REF		2.90 REF		
L2	0.020	BSC	0.51 BSC		
L3	0.035	0.050	0.89	1.27	
L4		0.040		1.01	
Z	0.155		3.93		





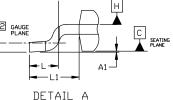


BOTTOM VIEW

5.80

BOTTOM VIEW ALTERNATE

CONSTRUCTIONS [0.228] 6.20 L2 GAUGE PLANE [0.244] 2.58 3.00 [0.102] [0.118] 1.60 [0.063] 6.17



STYLE 5: PIN 1. GATE

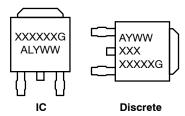
2. ANODE

3 CATHODE

ANODE

CW ROTATED 90°

## **GENERIC MARKING DIAGRAM\***



= Device Code
= Assembly Location
= Wafer Lot
= Year
= Work Week
= Pb-Free Package

RECOMMENDED MOUNTING FOOTPRINT\* \*FOR ADDITIONAL INFORMATION ON OUR PB-FREE STRATEGY AND SOLDERING DETAILS, PLEASE DUWNLOAD THE ON SEMICONDUCTOR SOLDERING AND MOUNTING TECHNIQUES REFERENCE MANUAL, SOLDERRM/D.

[0.243]

STYLE 1: PIN 1. BASE STYLE 2: PIN 1. GATE STYLE 3: PIN 1. ANODE STYLE 4: PIN 1. CATHODE 2. COLLECTOR 2. DRAIN 2. CATHODE 2. ANODE 3 SOURCE 3 FMITTER 3 ANODE 3 GATE

COLLECTOR 4. DRAIN 4. CATHODE 4. ANODE STYLE 6: STYLE 7: PIN 1. GATE 2. COLLECTOR STYLE 8: STYLE 9: PIN 1. MT1 2. MT2

STYLE 10: PIN 1. N/C 2. CATHODE 3. ANODE PIN 1. ANODE 2. CATHODE PIN 1. CATHODE 2. ANODE 3 CATHODE 3 FMITTER 3 RESISTOR ADJUST 4. COLLECTOR 4. CATHODE 4. ANODE CATHODE

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "■", may or may not be present. Some products may not follow the Generic Marking.

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DESCRIPTION:	DPAK (SINGLE GAUGE)		PAGE 1 OF 1	

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3 GATE

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